NEC

MOS INTEGRATED CIRCUIT

μPD16700

256-OUTPUT TFT-LCD GATE DRIVER

DESCRIPTION

The μPD16700 is a TFT-LCD gate driver equipped with 256-output lines. It can output a high-gate scanning voltage in response to CMOS level input because it provided with a level-shift circuit inside the IC circuit. It can also drive the XGA/SXGA panel.

FEATURES

- CMOS level input (3.3 V)
- 256 outputs
- High-output voltage (V_{DD2}-V_{EE2} = amplitude: 40 V MAX.)
- Capable of All-on outputting (/AO)

Remark /xxx indicates active low signal.

ORDERING INFORMATION

Part Number	Package
μPD16700N-xxx	TCP (TAB package)

Remark The TCP's external shape is customized. To order the required shape, please contact an one of our sales representatives.

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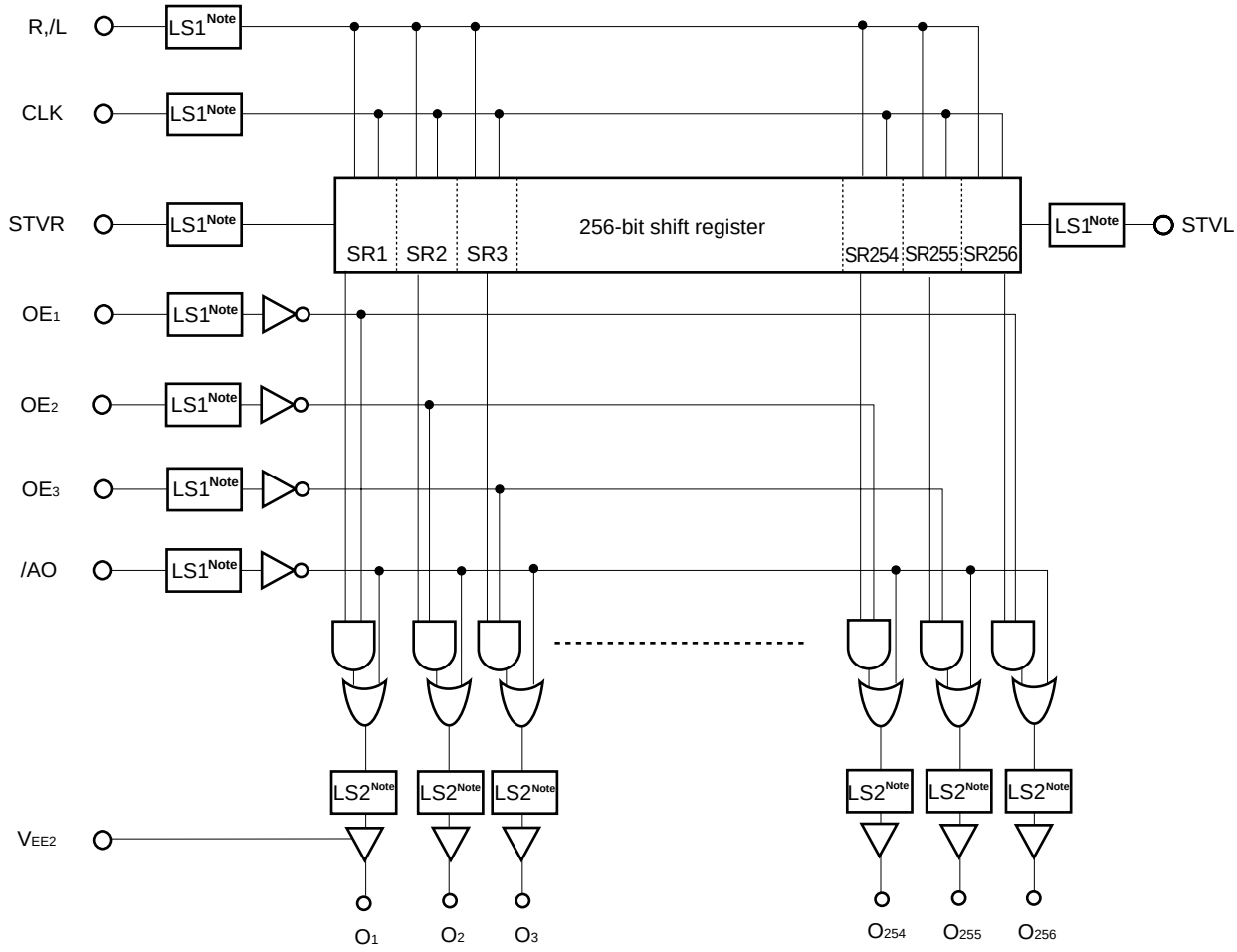
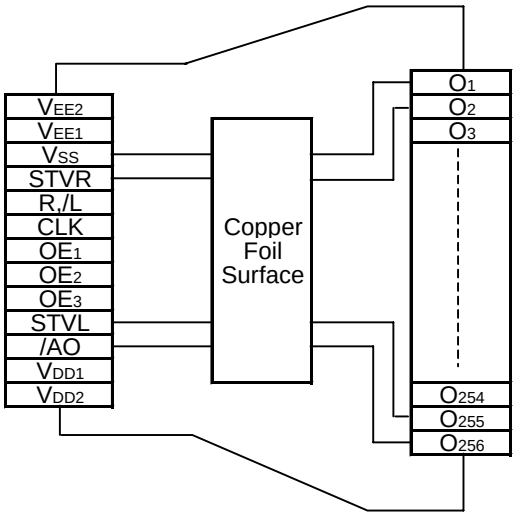
The mark ★ shows major revised points.

1. BLOCK DIAGRAM



Note LS1: shifts CMOS level and internal level, LS2: shifts interval level and output level (V_{DD2}-V_{EE2}).

2. PIN CONFIGURATION (μPD16700N-xxx : Copper Foil Surface, Face-up)



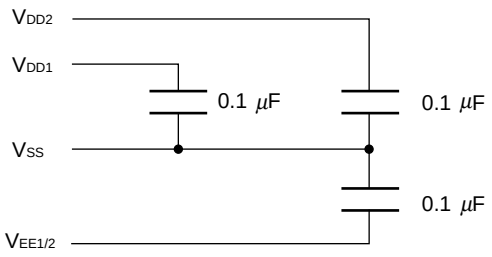
Remark This figure does not specify the TCP package.

3. PIN FUNCTIONS

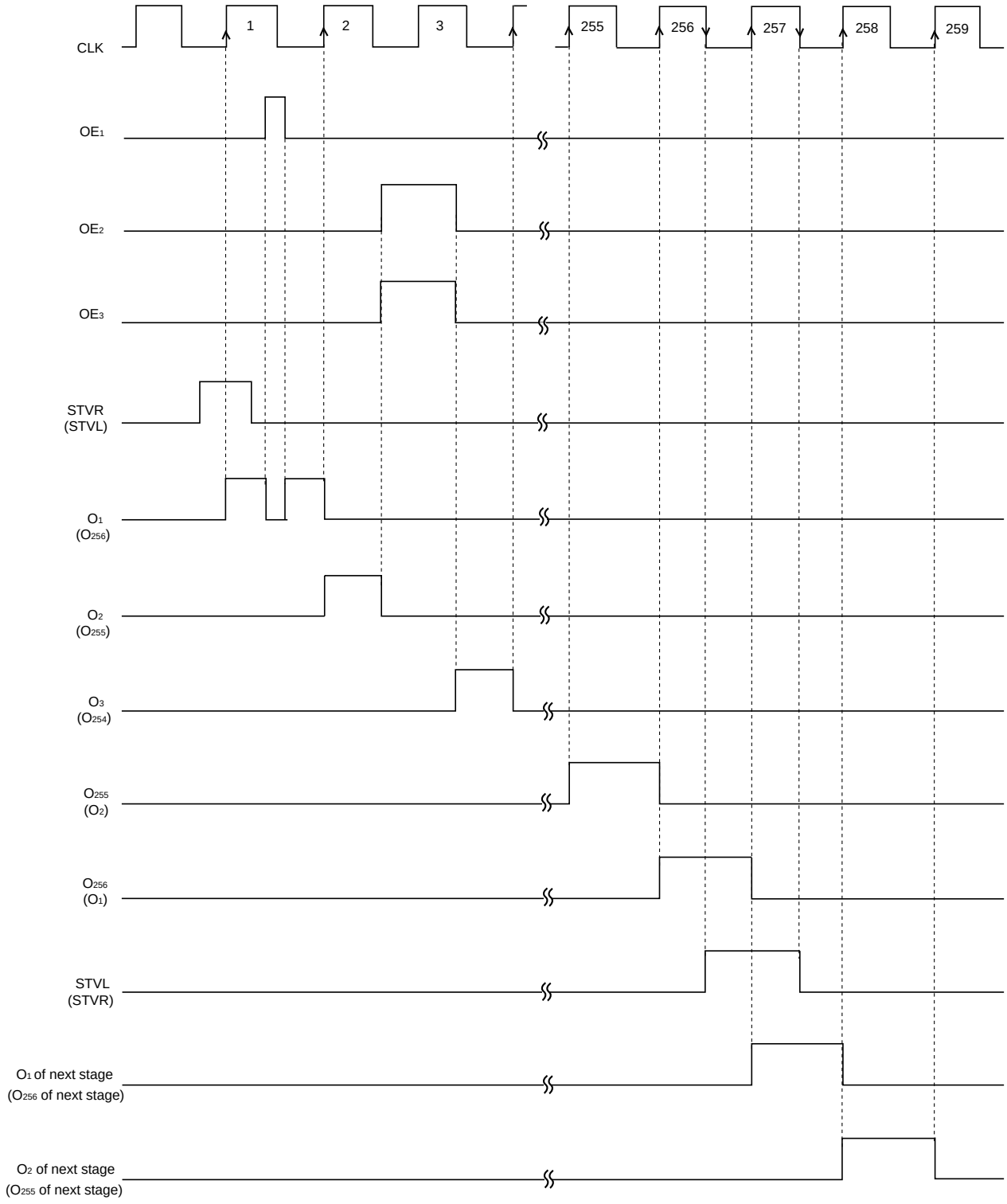
Pin Symbol	Pin Name	I/O	Description
O_1 to O_{256}	Driver	O	These pins output scan signals that drive the vertical direction (gate lines) of a TFT-LCD. The output signals change in synchronization with the rising edge of shift clock (CLK). The driver output amplitude is V_{DD2} - V_{EE2}.
R,/L	Shift direction select	I	Refers to the shift direction control. The shift directions of shift registers are as follows. R,/L = H (right shift) : STVR → O_1 → O_{256} → STVL R,/L = L (left shift) : STVL → O_{256} → O_1 → STVR
★ STVR, STVL	Start pulse	I/O	These refer to the input pins of the internal shift register. The start pulse is read at the rising edge of CLK, and scan signals are output from the driver output pins. The input level is a CMOS (3.3 V) level. The start pulse is output at the falling edge of the 256th clock of CLK, and is cleared at the falling edge of the 257th clock. The output level is V_{DD1} - V_{SS} (logic level). The output level is a CMOS level (3.3 V).
CLK	Shift clock	I	This pin inputs a shift clock to the internal shift register. The shift operation is performed in synchronization with the rising edge of this input.
★ OE_1 to OE_3	Output enable	I	When these pins go H, the driver output is fixed to V_{EE2} level. The shift registers are not cleared. These pins are not synchronous with CLK. OE_1: O_1, O_4, ... O_{250}, O_{253}, O_{256} OE_1: O_2, O_5, ... O_{251}, O_{254} OE_1: O_3, O_6, ... O_{252}, O_{255}
★ /AO	All-on control	I	When this pin goes L, the driver output is fixed to V_{DD2} level. The shift register is not cleared. This pin has priority over OE_1 to OE_3. This pin is not synchronous with CLK.
V_{DD1}	Logic power supply	–	3.3 V ± 0.3 V
V_{DD2}	Driver positive power supply	–	15 to 25 V The driver output : H level
V_{SS}	Logic ground	–	Connect this pin to the ground of the system.
V_{EE1}	Negative Power supply for internal operation	–	–15 to –5 V
V_{EE2}	Driver negative power supply	–	The driver output : L level (V_{EE2}-V_{EE1} < 6.0 V)

Cautions 1. To prevent latch up, turn on power to V_{DD1}, $V_{EE1/2}$, V_{DD2}, and logic input in this order. Turn off power in the reverse order. These power up/down sequence must be observed also during transition period.

2. Insert a capacitor of about 0.1 μF between each power line, as shown below, to secure noise margin such as V_{IH} and V_{IL}.



4. TIMING CHART (R,/L = H, /AO = H)



5. ELECTRICAL SPECIFICATIONS

Absolute Maximum Ratings (T_A = 25°C, V_{SS} = 0 V)

Parameter	Symbol	Rating	Unit
Logic Supply Voltage	V_{DD1}	–0.5 to +7.0	V
Driver Positive Supply Voltage	V_{DD2}	–0.5 to +28	V
Power Supply Voltage	V_{DD2}-V_{EE1}, V_{EE2}	–0.5 to +42	V
Internal Operation Negative Supply Voltage	V_{EE1}	–16 to + 0.5	V
Driver Negative Supply Voltage	V_{EE2}	V_{EE1} – 0.3 to V_{EE1} + 7.0	V
Input Voltage	V_I	–0.5 to V_{DD1} + 0.5	V
Operating Ambient Temperature	T_A	–20 to +75	°C
Storage Temperature	T_{stg}	–55 to +125	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Recommended Operating Range (T_A = –20 to +75°C, V_{SS} = 0 V)

Parameter	Symbol	MIN.	TYP.	MAX.	Unit
Logic Supply Voltage	V_{DD1}	3.0	3.3	3.6	V
Driver Positive Supply Voltage	V_{DD2}	15	23	25	V
Internal Operation Negative Supply Voltage	V_{EE1}	–15	–10	–5.0	V
Power Supply Voltage	V_{DD2}-V_{EE1}	20	33	40	V
	V_{EE2}-V_{EE1}	0		6.0	V
Clock Frequency	f_{CLK}			100	kHz

Electrical Characteristics (T_A = –20 to +75°C, V_{DD1} = 3.3 V ± 0.3 V, V_{DD2} = 23 V, V_{EE1} = V_{EE2} = –10 V, V_{SS} = 0 V)

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
High-level Input Voltage	V_{IH}	CLK, STVR (STVL), R,/L,	0.8 V_{DD1}		V_{DD1}	V
Low-level Input Voltage	V_{IL}	OE_1-OE_3	V_{SS}		0.2 V_{DD1}	V
High-level Output Voltage	V_{OH}	STVR (STVL), I_{OH} = –40 μA	V_{DD1} – 0.4		V_{DD1}	V
Low-level Output Voltage	V_{OL}	STVR (STVL), I_{OL} = +40 μA	V_{SS}		V_{SS} + 0.4	V
★ LCD Driver Output ON Resistance	R_{ON}	V_{OUT} = V_{EE2} + 1.0 V, or V_{DD2} – 1.0 V		0.25	1.0	kΩ
Input Leak Current	I_{IL}	V_I = 0 V or 3.6 V			±1.0	μA
Static Current Dissipation	I_{DD1}	V_{DD1}, f_{CLK} = 50 kHz, OE_1 = OE_2 = OE_3 = L, f_{STV} = 60 Hz, no load		500	1000	μA
	I_{DD2}	V_{DD2}, f_{CLK} = 50 kHz, OE_1 = OE_2 = OE_3 = L, f_{STV} = 60 Hz, no load		50	100	μA
	I_{EE}	V_{EE1}, f_{CLK} = 50 kHz, OE_1 = OE_2 = OE_3 = L, f_{STV} = 60 Hz, no load	–1100	–550		μA

Switching Characteristics (T_A = –20 to +75°C, V_{DD1} = 3.3 V ± 0.3 V, V_{DD2} = 23 V, V_{EE1} = V_{EE2} = –10 V, V_{SS} = 0 V)

Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
★ Cascade Output Delay Time	t_{PHL1}	C_L = 20 pF,		240	800	ns
★	t_{PLH1}	CLK → STVL (STVR)		240	800	ns
★ Driver Output Delay Time	t_{PHL2}	C_L = 300 pF, CLK → O_n		240	800	ns
★	t_{PLH2}			240	800	ns
★	t_{PHL3}	C_L = 300 pF, OE_n → O_n		240	800	ns
★	t_{PLH3}			240	800	ns
Output Rise Time	t_{TLH}	C_L = 300 pF			350	ns
Output Fall Time	t_{THL}				350	ns
★ Input Capacitance	C_I	T_A = 25 °C		6.0	15	pF

Timing Requirements (T_A = –20 to +75°C, V_{DD1} = 3.3 V ± 0.3 V, V_{DD2} = 23 V, V_{EE1} = V_{EE2} = –10 V, V_{SS} = 0 V)

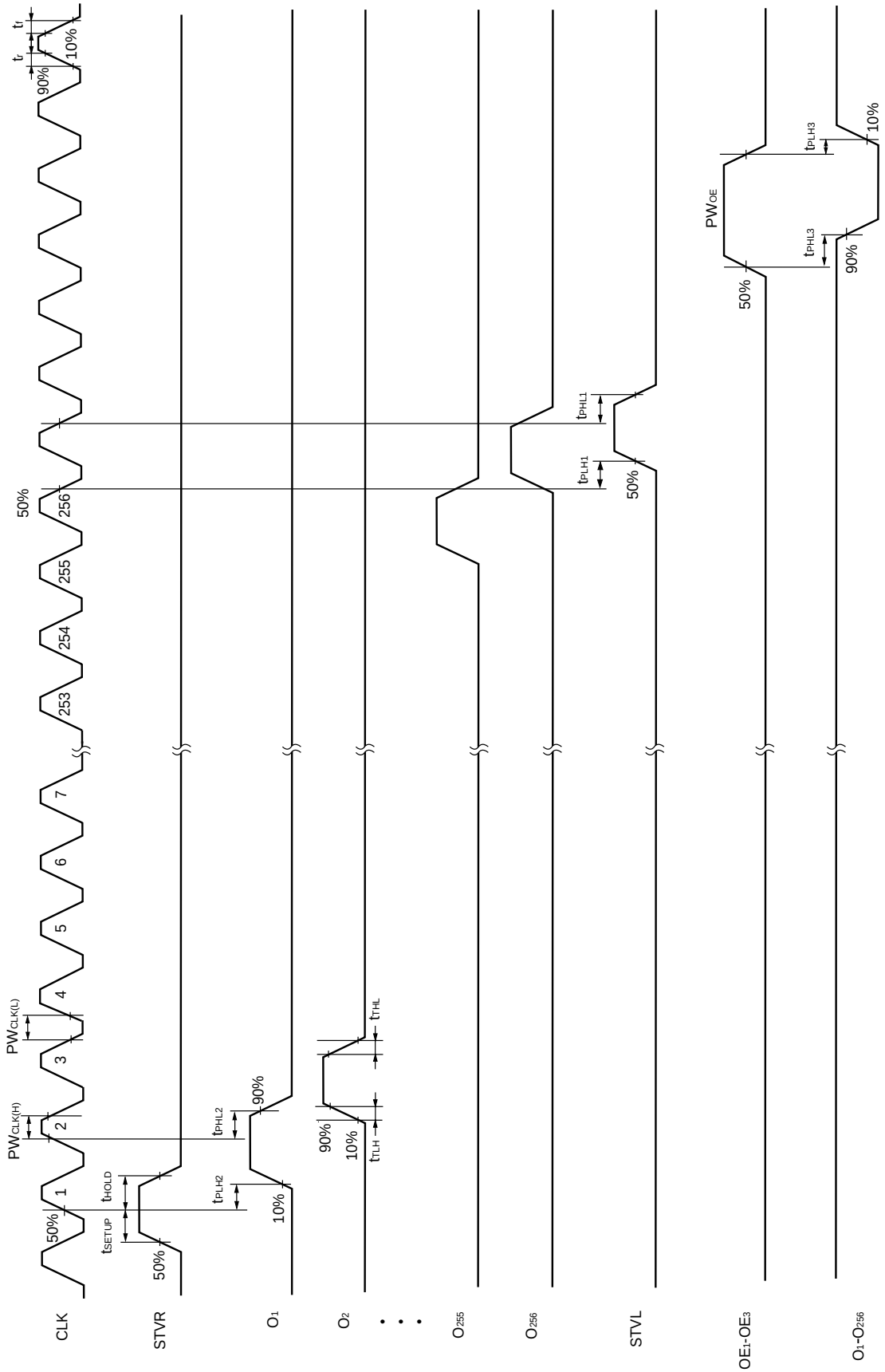
Parameter	Symbol	Condition	MIN.	TYP.	MAX.	Unit
Clock Pulse High Width	$PW_{CLK(H)}$		500			ns
Clock Pulse Low Width	$PW_{CLK(L)}$		500			ns
Enable Pulse Width	PW_{OE}		1.0			μs
Data Setup Time	t_{SETUP}	STVR (STVL) ↑ → CLK ↑	200			ns
Data Hold Time	t_{HOLD}	CLK ↑ → STVR(STVL) ↓	200			ns

Caution Keep the time and fall time of the logic input to t_r = t_f = 20 ns (10 to 90% of the rated values).

Remark Unless otherwise specified, the input level is defined to be V_{IH} = 0.8 V_{DD1}, V_{IL} = 0.2 V_{DD1}. For details, refer to **Switching Characteristic Waveform**.

Switching Characteristic Waveform (R,/L= H)

Unless otherwise specified, the input level is defined to be V_{IH} = 0.8 V_{DD1}, V_{IL} = 0.2 V_{DD1}.



6. RECOMMENDED MOUNTING CONDITIONS

The following conditions must be met for mounting conditions of the μPD16700.

For more details, refer to the **Semiconductor Device Mounting Technology Manual (C10535E).**

Please consult with our sales offices in case other mounting process is used, or in case the mounting is done under different conditions.

μPD16700N-xxx : TCP (TAB Package)

Mounting Condition	Mounting Method	Condition
Thermocompression	Soldering	Heating tool 300 to 350°C, heating for 2 to 3 seconds : pressure 100g (per solder)
	ACF (Adhesive Conductive Film)	Temporary bonding 70 to 100°C: pressure 3 to 8 kg/cm^2: time 3 to 5 sec. Real bonding 165 to 180°C: pressure 25 to 45 kg/cm^2: time 30 to 40 sec. (When using the anisotropy conductive film SUMIZAC1003 of Sumitomo Bakelite,Ltd).

Caution To find out the detailed conditions for mounting the ACF part, please contact the ACF manufacturing company. Be sure to avoid using two or more mounting methods at a time.

[MEMO]

NOTES FOR CMOS DEVICES

① PRECAUTION AGAINST ESD FOR SEMICONDUCTORS

Note:

Strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred. Environmental control must be adequate. When it is dry, humidifier should be used. It is recommended to avoid using insulators that easily build static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work bench and floor should be grounded. The operator should be grounded using wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with semiconductor devices on it.

② HANDLING OF UNUSED INPUT PINS FOR CMOS

Note:

No connection for CMOS device inputs can be cause of malfunction. If no connection is provided to the input pins, it is possible that an internal input level may be generated due to noise, etc., hence causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using a pull-up or pull-down circuitry. Each unused pin should be connected to V_{DD} or GND with a resistor, if it is considered to have a possibility of being an output pin. All handling related to the unused pins must be judged device by device and related specifications governing the devices.

③ STATUS BEFORE INITIALIZATION OF MOS DEVICES

Note:

Power-on does not necessarily define initial status of MOS device. Production process of MOS does not define the initial operation status of the device. Immediately after the power source is turned ON, the devices with reset function have not yet been initialized. Hence, power-on does not guarantee out-pin levels, I/O settings or contents of registers. Device is not initialized until the reset signal is received. Reset operation must be executed immediately after power-on for devices having reset function.

Reference Documents

NEC Semiconductor Device Reliability/Quality Control System (C10983E)

Quality Grades to NEC's Semiconductor Devices (C11531E)

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